Deep Learning Global Context Anomaly Detection in practice

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In visual inspection tasks, the appearance of defects often cannot be predicted. Over the last years, deep learning methods have been providing the means to develop parameter-free customer applications. However, the challenge has shifted to provide the appropriate data. A particular challenge is to find defects even if no or just a few data of that class is available. This presentation will show an easy-to-use way to master this challenge based on Deep Learning Global Context Anomaly Detection. By a practical example, an end-to-end workflow from the data to a deployable deep learning application will be presented using MVTec's Deep Learning Tool and MERLIC.